

# **MOSFET** - N-Channel, POWERTRENCH®

100 V, 5.6 A, 160 m $\Omega$ 

# FDT1600N10ALZ

# **General Description**

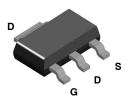
This N-Channel MOSFET is produced using **onsemi**'s advanced POWERTRENCH process that has been tailored to minimize the on-state resistance and maintain superior switching performance.

#### **Features**

- $R_{DS(on)} = 121 \text{ m}\Omega \text{ (Typ.)} @ V_{GS} = 10 \text{ V}, I_D = 2.8 \text{ A}$
- $R_{DS(on)} = 156 \text{ m}\Omega \text{ (Typ.)} @ V_{GS} = 5 \text{ V}, I_D = 1.8 \text{ A}$
- Low Gate Charge (Typ. 2.9 nC)
- Low C<sub>rss</sub> (Typ. 2.04 pF)
- Fast Switching
- 100% Avalanche Tested
- Improved dv/dt Capability
- RoHS Compliant

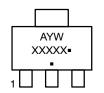
## **Applications**

- Consumer Appliances
- LED TV and Monitor
- Synchronous Rectification
- Uninterruptible Power Supply
- Micro Solar Inverter



SOT-223 CASE 318H

#### **MARKING DIAGRAM**



A = Assembly Location

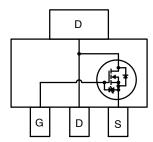
Y = Year

W = Work Week

X = Specific Device Code

■ = Pb-Free Package (Note: Microdot may be in either location)

#### **PIN ASSIGNMENT**



## **ORDERING INFORMATION**

See detailed ordering and shipping information on page 3 of this data sheet.

# **MOSFET MAXIMUM RATINGS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter			FDT1600N10ALZ	Unit
$V_{DSS}$	Drain to Source Voltage			100	V
V <sub>GSS</sub>	Gate to Source Voltage			±20	V
I <sub>D</sub>	Drain Current – Continuous (T <sub>C</sub> = 25°C)			5.6	Α
		- Continuous (T <sub>C</sub> = 100°C)		3.5	1
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 2)	11.2	Α
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 3)			9.2	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 4)			6.0	V/ns
$P_{D}$	Power Dissipation	(T <sub>C</sub> = 25°C)		10.42	W
		- Derate Above 25°C		0.083	°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C
TL	Maximum Lead Temperature for Soldering,1/8" from Case for 5 Seconds			300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## THERMAL CHARACTERISTICS

Symbol	Parameter	FDT1600N10ALZ	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case (Note 1)	12	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	60	

# 

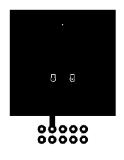
Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
OFF CHARA	ACTERISTICS						
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu\text{A},  V_{GS} = 0$	V	100	_	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Reference	ed to 25°C	-	0.1	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$	/	1	-	1	μΑ
		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$	/, T <sub>C</sub> = 125°C	1	-	500	
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0$	V	-	-	±10	μΑ
ON CHARAC	CTERISTICS						
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu$	ιA	1.4	-	2.8	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2.8 A		-	121	160	mΩ
		V <sub>GS</sub> = 5 V, I <sub>D</sub> = 1.8 A		-	156	375	
9FS	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 5.6 A		-	26.1	-	S
DYNAMIC C	HARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz		-	169	225	pF
Coss	Output Capacitance			-	43	55	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			-	2.04	-	pF
C <sub>oss(er)</sub>	Energy Related Output Capacitance	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V		-	85	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10 V	V <sub>GS</sub> = 10 V	V <sub>DD</sub> = 50 V,	-	2.9	3.77	nC
Q <sub>g(tot)</sub>	Total Gate Charge at 5 V	V <sub>GS</sub> = 5 V	I <sub>D</sub> = 5.6 A	-	1.6	2.08	nC
Q <sub>gs</sub>	Gate to Source Gate Charge			-	0.7	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	]		-	0.64	-	nC
V <sub>plateau</sub>	Gate Plateau Volatge	<u>]</u>	(Note 5)	-	3.81	-	V
Q <sub>sync</sub>	Total Gate Charge Sync.	$V_{DS} = 0 \text{ V}, I_D = 2.8 \text{ A}$	V <sub>DS</sub> = 0 V, I <sub>D</sub> = 2.8 A		2.45	-	nC
Q <sub>oss</sub>	Output Charge	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V		5.2	_	nC

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted) (continued)

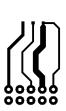
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
ESR	Equivalent Series Resistance (G-S)	f = 1 MHz	_	2.1	_	Ω
WITCHING	CHARACTERISTICS					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 5.6 A,	-	7.4	24.8	ns
t <sub>r</sub>	Rise Time	$V_{GS} = 10 \text{ V}, R_G = 4.7 \Omega$	=	2.5	15	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		-	13.5	37	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 5)	-	2.4	14.8	ns
RAIN-SOL	IRCE DIODE CHARACTERISTICS					
I <sub>S</sub>	Maximum Continous Drain to Source Diode Forward Current		-	-	5.6	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		=	-	11.2	Α
$V_{SD}$	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 5.6 A	-	-	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{SD} = 5.6 \text{ A}, V_{DD} = 50 \text{ V}$	-	34.1	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> /dt = 100 A/μs	_	32.7	-	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>1.</sup>  $R_{\theta JA}$  is the sum of the junction–to–case and case–to–ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a. 60°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b.  $118^{\circ}\text{C/W}$  when mounted on a minimum pad of 2 oz copper

- 2. Repetitive rating: pulse-width limited by maximum junction temperature.
- 3. Starting  $T_J = 25^{\circ}C$ , L = 3 mH,  $I_{AS} = 2.47$  A.
- 4.  $I_SD \le 5.6$  Å, di/dt  $\le 200$  Å/ $\mu$ s,  $V_{DD} \le BV_{DSS}$ , starting  $T_J = 25^{\circ}C$ .
- 5. Essentially independent of operating temperature typical characteristics.

#### PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Mark	Package	Reel Size	Tape Width	Shipping <sup>†</sup>
FDT1600N10ALZ	16010ALZ	SOT-223	13"	12 mm	4000/ Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, <a href="https://example.com/BRD8011/D">BRD8011/D</a>.

## **TYPICAL CHARACTERISTICS**

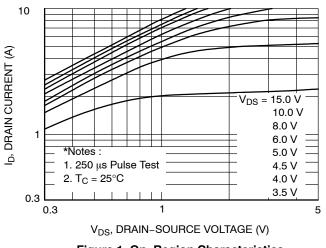


Figure 1. On-Region Characteristics

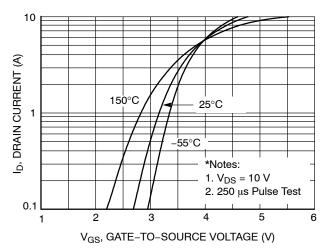


Figure 2. Transfer Characteristics

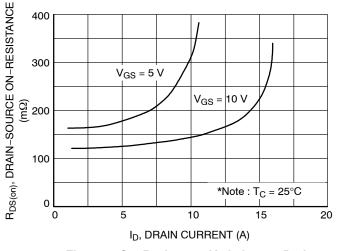


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

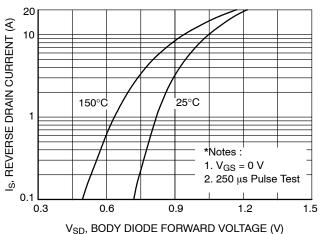


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

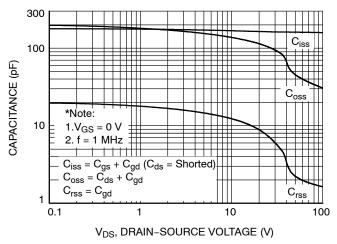


Figure 5. Capacitance Characteristics

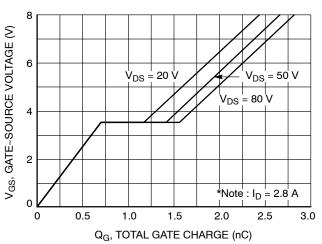


Figure 6. Gate Charge Characteristics

#### TYPICAL CHARACTERISTICS (continued)

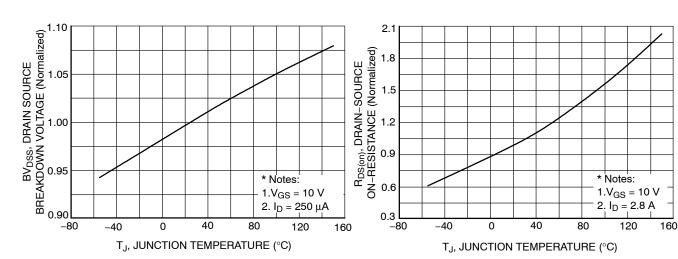


Figure 7. Breakdown Voltage Variation vs. Temperature

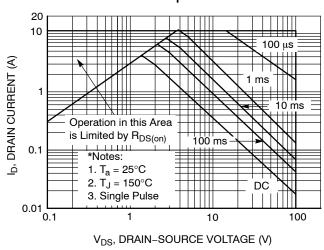


Figure 9. Maximum Safe Operating Area

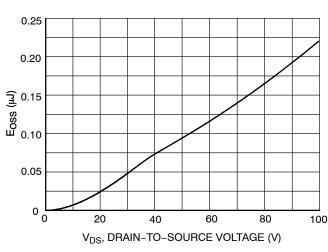


Figure 11. E<sub>OSS</sub> vs. Drain-to-Source Voltage



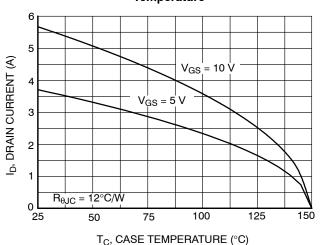


Figure 10. Maximum Drain Current vs. Case Temperature

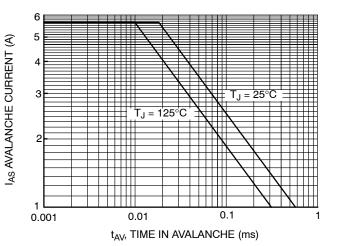


Figure 12. Unclamped Inductive Switching Capability

# TYPICAL CHARACTERISTICS (continued)

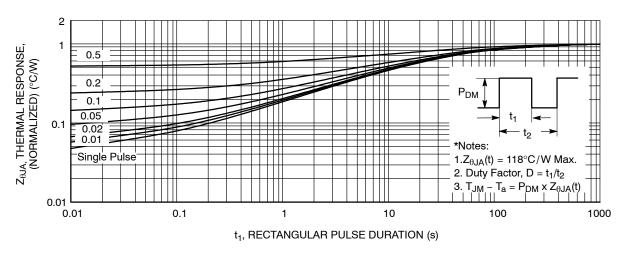


Figure 13. Transient Thermal Response Curve

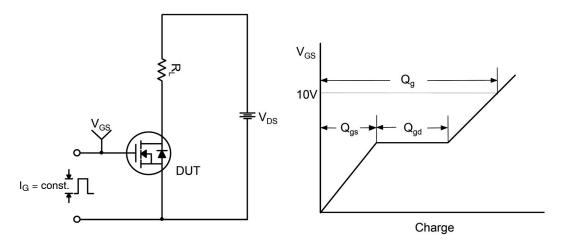


Figure 14. Gate Charge Test Circuit & Waveform

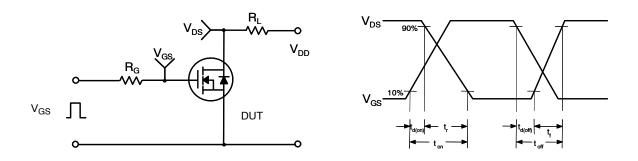


Figure 15. Resistive Switching Test Circuit & Waveforms

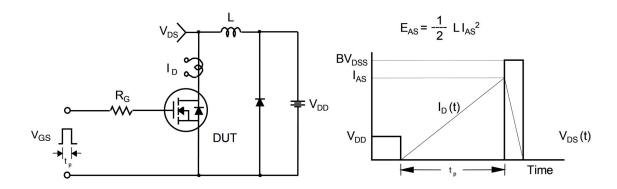


Figure 16. Unclamped Inductive Switching Test Circuit & Waveforms

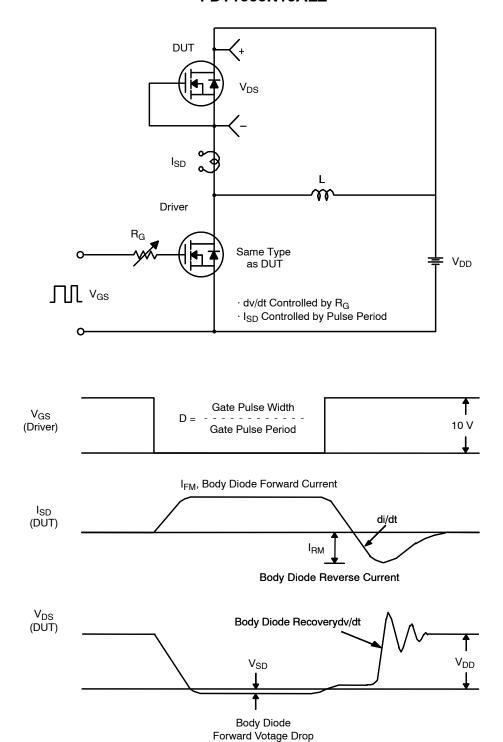


Figure 17. Peak Diode Recovery dv/dt Test Circuit & Waveforms

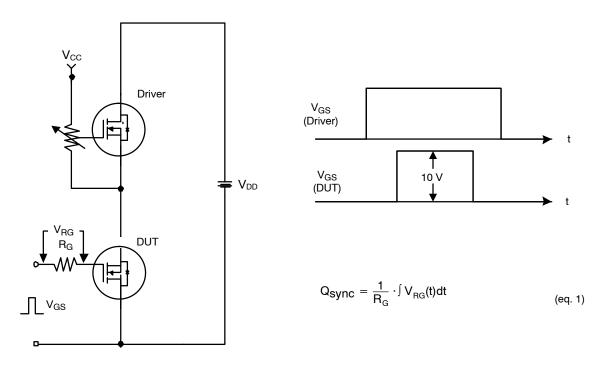


Figure 18. Total Gate Charge Qsync. Test Circuit & Waveforms

SCALE 2:1



A

В

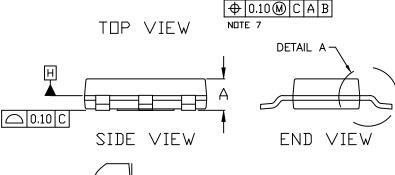
**DATE 13 MAY 2020** 

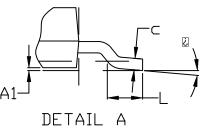
#### NOTES

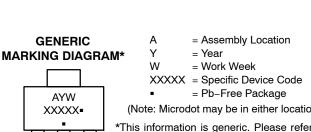
- DIMENSIONING AND TOLERANCING PER ASME
- DIMENSIDNING AND TOLERANCING PER ASME
  Y14.5M, 2009.
  CONTROLLING DIMENSION: MILLIMETERS
  DIMENSIONS D & E1 ARE DETERMINED AT DATUM
  H. DIMENSIONS DO NOT INCLUDE MOLD FLASH,
  PROTRUSIONS DR GATE BURRS. SHALL NOT
  EXCEED 0.23mm PER SIDE.
  LEAD DIMENSIONS & AND &1 DO NOT INCLUDE
  DAMBAR PROTRUSION. ALLOWABLE DAMBBAR
  PROTRUSION IS 0.08mm PER SIDE.
  DATUMS A AND B ARE DETERMINED AT DATUM H.
  A1 IS DEFINED AS THE VERTICAL DISTANCE
  FROM THE SEATING PLANE TO THE LOWEST
  POINT OF THE PACKAGE BODY.
  POSITIONAL TOLERANCE APPLIES TO DIMENSIONS
  & AND &1.

- b AND b1.

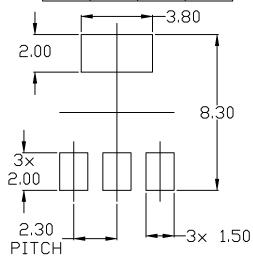
	MILLIMETERS				
DIM	MIN.	N□M.	MAX.		
Α			1.80		
A1	0.02	0.06	0.11		
b	0.60	0.74	0.88		
b1	2.90	3.00	3.10		
c	0.24		0.35		
D	6.30	6.50	6.70		
E	6.70	7.00	7.30		
E1	3.30	3.50	3.70		
е	2.30 BSC				
L	0.25				
Ŀ	0*		10°		







(Note: Microdot may be in either location) \*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.



## RECOMMENDED MOUNTING FOOTPRINT

For additional information on our Pb-Free strategy and soldering details, please download the IN Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	SOT-223		PAGE 1 OF 1	

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